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Substitute for form 1449A/P INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/620.628
				Filing Date	7/15/2003
				First Named Inventor:	John X. Zhong
				Examiner: Stacy Whitmore	GROUP: 2812 2825
Sheet	1	of	1	Attorney Docket Number	SYN-0551CON1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cited No. ¹	Document Number Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear
<i>AW</i>	A01	US-5,910,897	06/1999	Dangelo	
<i>AW</i>	A02	US-6,295,623	B1	Lesmeister	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Cntry Code ³ Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear	T ⁶

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>AW</i>	Martinolle, F. et al. "A procedural language interface for VHDL and its typical applications," Jan. 1998, ACM, pp. 32-38
	Gough, G. et al. "A design and verification environment for ELLA," Sep. 1995, IEEE, pp. 685-690
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	Dawson, C. et al. "The verilog procedural interface for the verilog hardware description language," 1996, IEEE, pp. 17-22
	Meyer, S. "Verilog plus c language modeling with PLI 2.0: the next generation simulation language," Mar. 1998, IEEE, pp. 98-105
<i>AW</i>	York, G. "An integrated environment for HDL verification," Mar. 1995, IEEE, pp. 9-18

EXAMINER SIGNATURE: <i>[Signature]</i>	DATE CONSIDERED: 12/8/05
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